

RECEIVED

11-13 DEC 3 0

OFFICE OF ENROLLMENT  
AND DISCIPLINE

IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

RESPONSE UNDER 37 CFR 1.116  
EXPEDITED PROCEDURE  
EXAMINING GROUP 2829

PATENT APPLICATION

Docket No. 8750-17

Client No. SPX2001100010US

In re application of: Sang-Eun LEE and JAe-Sung HAN

Serial No. 10/068,152

Examiner: Hollinton, Jermele M.

Confirmation No. 7500

Filed: February 6, 2002

Art Unit: 2829

For: METHOD OF IDENTIFYING AND ANALYZING SEMICONDUCTOR  
CHIP DEFECTS

MAIL STOP AF  
Commissioner for Patents  
P.O. Box 1450  
Alexandria, VA 22313-1450

Responsive to the Final Office Action dated September 25, 2003, enclosed is an amendment  
in the above-identified application.

The fee has been calculated as shown below.

<u>CLAIMS AS AMENDED</u>					
For:	Number After Amendment	Previous Number	Extra	Rate	Additional Fee
Total Claims	20	20	0	x \$18 =	\$0
Independent Claims	3	3	0	x \$86 =	\$0
TOTAL ADDITIONAL FEE FOR THIS AMENDMENT					\$0

\*greater of twenty (20) or number for which fee has been paid

\*\*greater of three (3) or number for which fee has been paid

Any deficiency or overpayment should be charged or credited to deposit account number 13-1703.

Customer No. 20575

Respectfully submitted,

MARGER JOHNSON & McCOLLOM, P.C.

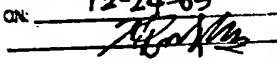
Kevin S. Ross  
Reg. No. 42,116

MARGER JOHNSON & McCOLLOM, P.C.  
1030 SW Morrison Street  
Portland, OR 97205  
(503) 222-3613

I HEREBY CERTIFY THAT  
THIS CORRESPONDENCE IS  
BEING DEPOSITED WITH THE  
UNITED STATES POSTAL  
SERVICE AS FIRST CLASS  
MAIL IN AN ENVELOPE  
ADDRESSED TO:

COMMISSIONER OF PATENTS  
AND TRADEMARKS WASHINGTON  
D.C. 20231

MAIL STOP AF  
COMMISSIONER FOR PATENTS  
BOX 1450  
ALEXANDRIA, VA 22313-1450

BOX  
COMMISSIONER  
FOR TRADEMARKS 2900 CRYSTAL  
DRIVE ARLINGTON, VA 22222-3816  
ON: 12-24-03  


RECEIVED

2003 DEC 30

OFFICE OF ENROLLMENT  
AND DISCIPLINE

RESPONSE UNDER 37 CFR 1.116  
EXPEDITED PROCEDURE  
EXAMINING GROUP 2829

PATENT APPLICATION  
Docket No. 8750-17  
Client No. SPX2001100010US

IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

In re application of: Sang-Eun LEE and JAe-Sung HAN

Serial No. 10/068,152 Examiner: Hollinton, Jermele M.

Confirmation No. 7500

Filed: February 6, 2002 Art Unit: 2829

For: METHOD OF IDENTIFYING AND ANALYZING SEMICONDUCTOR  
CHIP DEFECTS

Mail Stop AF  
Commissioner for Patents  
P.O. Box 1450  
Alexandria, VA 22313-1450

**RESPONSE AFTER FINAL REJECTION UNDER 37 CFR 1.116**

Responsive to the Final Office Action, Paper No. 5, dated September 25, 2003, please amend the application as follows.

**Amendments to the Claims** are reflected in the listing of claims which begins on page 2 of this paper.

**Remarks/Arguments** begin on page 5 of this paper.

RECEIVED  
JMN - 2 2003  
TECHNOLOGY CENTER 2800